

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/721,512	<b>Applicant(s)/Patent under Reexamination</b> KOBAYASHI ET AL.
	<b>Examiner</b> Hai V. Nguyen	<b>Art Unit</b> 2142

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner